www.SeCosGmbH.com

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8F.No.33, Lane 155, Sec.3, Bei-Shen Rd.,
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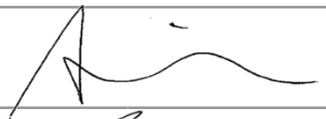
Product/Process Change Notification

PCN#	Effective Date	Issue Date
2020-06-01C-01	2021/1/1	2020/6/1
PCN Classification	**Product Category**	
Major	SST3585S	
Subject		
Change assembly factory		
Affected Product(s)		
SST3585S		
Description of Change(s)		
Original assembly factory EOL, thus Change assembly factory.		
Content of Change(s)		
Assembly vendor		
Impact(s)		
N/A		
Attachment(s)		
Reliability Teat Report.		

Approval		
Issue by	Alice Lai	e-mail: alice@secosgmbh.com
Development Engineer		Alice Lai
QA Manager		Peter Yang
General Manger		Mathew Liu

For more information, please contact us directly or visit our website http://www.secosgmbh.com

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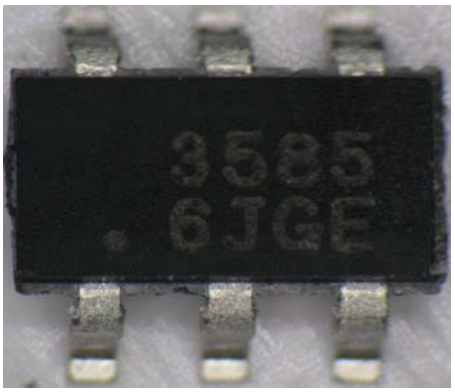
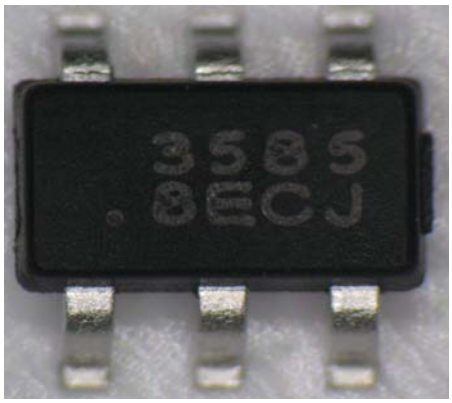
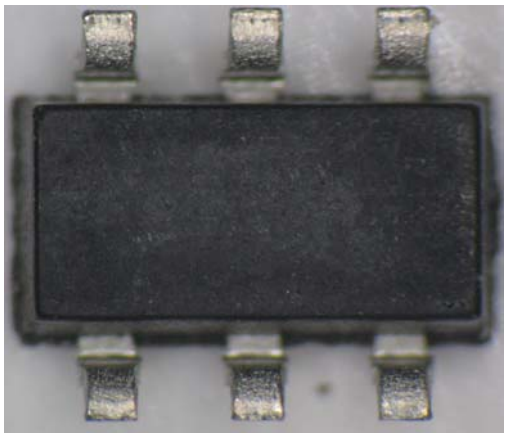
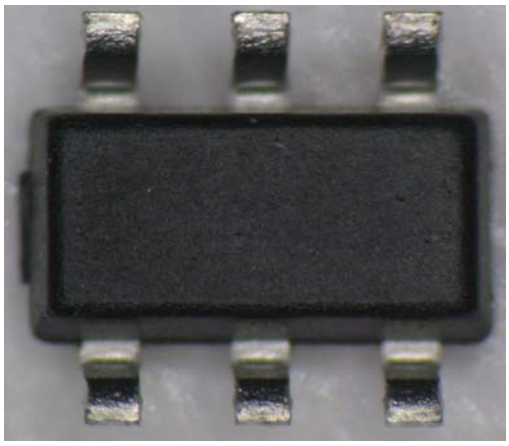
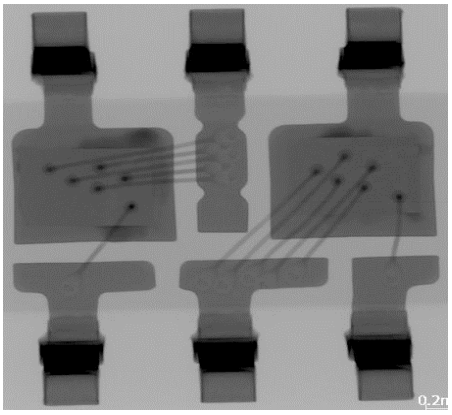
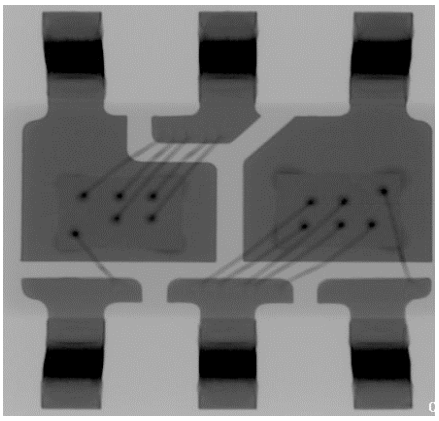
Exterior comparison Chart	
Original	New
	
Top View	Top View
	
Lateral View	Lateral View
	
X-Ray	X-Ray

SeCoS Corporation

Reliability Testing Summary Report

Date: 2020/05/29 Document No.: SN20 -05-T3585S

Test Item	P/N	Test Condition	(LTPD)	Sample Numbers	Allow Fall Numbers	Fall Numbers	Result
HTRB High Temp Reverse Bias	SST3585S-C	150 ± 5℃, 80%VR, T = 1000hrs		77	0	0	ACC
HTSL High Temperature Storage Life	SST3585S-C	150℃, T = 1000 hrs		77	0	0	ACC
PCT Pressure Cooker Test	SST3585S-C	121℃, 29.7PSIG, 168 hrs		77	0	0	ACC
TCT Temperature Cycle Test	SST3585S-C	-55℃/30min, 150℃/30min, For 1000 Cycle		77	0	0	ACC
THT High Temperature High Humidity Test	SST3585S-C	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
H3TRB High Temper High Humidity Reverse Bies Test	SST3585S-C	85 ± 2℃, RH=85±5%, 1000 hrs		77	0	0	ACC
Resistance to Solder Heat Test	SST3585S-C	270℃±5℃, 7Sec +2/-0Sec		77	0	0	ACC

Judgment:

■ **qualified** □ **unqualified**

Testing Start Date: 2020.04.06 Testing End Date: 2020.05.29

Tester: King Huang Approval: Peter Yang

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs

Test Date: 2020.04.06 ~ 2020.05.19

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.003	0.785	48.36	0.006	0.811	49.26	-0.002	-0.759	75.90	-0.001	-0.667	77.01
2	0.004	0.790	38.72	0.007	0.788	51.53	-0.000	-0.659	74.94	-0.001	-0.708	76.96
3	0.006	0.788	44.07	0.002	0.791	28.98	-0.000	-0.760	73.85	-0.001	-0.697	78.66
4	0.003	0.798	48.53	0.006	0.824	36.41	-0.002	-0.676	76.15	-0.002	-0.696	73.84
5	0.003	0.783	32.32	0.002	0.779	35.69	-0.002	-0.710	77.83	-0.003	-0.739	74.46
6	0.006	0.821	32.73	0.006	0.792	41.32	-0.000	-0.665	77.80	-0.001	-0.717	75.60
7	0.002	0.809	35.87	0.006	0.796	42.27	-0.000	-0.668	76.04	-0.001	-0.758	75.55
8	0.006	0.797	35.59	0.006	0.780	38.07	-0.002	-0.744	74.76	-0.000	-0.726	73.55
9	0.005	0.797	51.33	0.006	0.797	30.15	-0.001	-0.661	76.26	-0.001	-0.713	74.10
10	0.003	0.810	45.65	0.007	0.815	32.67	-0.002	-0.739	73.66	-0.001	-0.743	76.80
11	0.007	0.793	47.56	0.004	0.829	31.83	-0.002	-0.668	78.21	-0.001	-0.721	76.08
12	0.005	0.778	35.46	0.004	0.799	46.98	-0.002	-0.729	77.16	-0.000	-0.747	75.19
13	0.005	0.821	32.12	0.007	0.795	48.76	-0.001	-0.677	75.83	-0.001	-0.679	76.81
14	0.007	0.778	29.71	0.005	0.816	35.82	-0.003	-0.718	77.50	-0.001	-0.692	75.74
15	0.007	0.793	39.38	0.001	0.788	36.28	-0.000	-0.731	78.10	-0.002	-0.764	78.66
16	0.004	0.809	38.83	0.002	0.796	46.71	-0.002	-0.691	74.03	-0.001	-0.698	75.93
17	0.002	0.825	36.42	0.003	0.823	50.31	-0.001	-0.745	76.18	-0.001	-0.763	74.07
18	0.003	0.812	35.98	0.006	0.787	29.15	-0.003	-0.760	75.45	-0.002	-0.700	73.87
19	0.002	0.801	38.39	0.001	0.805	41.80	-0.003	-0.733	77.74	-0.000	-0.701	74.22
20	0.003	0.800	44.57	0.002	0.825	38.86	-0.002	-0.671	76.41	-0.001	-0.669	74.72
21	0.001	0.799	32.40	0.006	0.806	30.82	-0.001	-0.680	75.60	-0.002	-0.717	74.30
22	0.000	0.830	48.65	0.004	0.779	46.20	-0.002	-0.756	74.05	-0.000	-0.671	75.61
23	0.001	0.783	49.47	0.004	0.795	50.49	-0.001	-0.674	74.55	-0.002	-0.729	78.31
24	0.006	0.802	49.95	0.004	0.823	33.71	-0.000	-0.733	77.73	-0.001	-0.753	78.52
25	0.001	0.802	37.61	0.004	0.785	29.00	-0.002	-0.763	78.43	-0.000	-0.760	75.71
26	0.004	0.825	28.63	0.006	0.813	39.85	-0.000	-0.686	77.18	-0.002	-0.676	74.83
27	0.004	0.822	36.30	0.003	0.821	40.45	-0.003	-0.663	73.68	-0.000	-0.710	76.26

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs

Test Date: 2020.04.06 ~ 2020.05.19

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.001	0.782	44.65	0.003	0.802	43.31	-0.000	-0.673	74.15	-0.003	-0.664	77.95
29	0.002	0.817	50.19	0.006	0.784	40.17	-0.002	-0.721	74.19	-0.002	-0.714	76.07
30	0.002	0.801	44.71	0.002	0.814	44.45	-0.002	-0.695	74.13	-0.002	-0.705	74.66
31	0.001	0.781	30.78	0.007	0.804	43.25	-0.003	-0.724	78.61	-0.002	-0.715	73.84
32	0.001	0.791	29.95	0.002	0.818	31.46	-0.002	-0.721	73.75	-0.002	-0.736	76.87
33	0.002	0.809	28.91	0.004	0.815	41.68	-0.002	-0.715	74.25	-0.001	-0.678	73.79
34	0.004	0.781	46.28	0.005	0.810	43.38	-0.001	-0.759	74.84	-0.001	-0.701	76.31
35	0.005	0.812	34.25	0.006	0.794	42.82	-0.002	-0.679	73.84	-0.002	-0.681	76.28
36	0.007	0.797	42.73	0.007	0.808	29.73	-0.001	-0.706	78.11	-0.001	-0.720	78.16
37	0.005	0.812	42.59	0.007	0.817	45.49	-0.003	-0.759	77.48	-0.003	-0.762	77.50
38	0.007	0.807	38.45	0.002	0.789	51.88	-0.001	-0.719	74.38	-0.002	-0.699	77.49
39	0.004	0.778	50.26	0.001	0.821	43.76	-0.001	-0.659	77.38	-0.001	-0.748	73.70
40	0.002	0.828	42.31	0.000	0.787	49.05	-0.000	-0.709	75.89	-0.001	-0.714	74.79
41	0.003	0.826	49.89	0.005	0.799	35.19	-0.002	-0.750	74.42	-0.001	-0.748	76.68
42	0.007	0.791	43.01	0.004	0.781	39.66	-0.002	-0.756	75.67	-0.001	-0.660	76.40
43	0.002	0.804	35.34	0.004	0.795	38.20	-0.002	-0.748	76.15	-0.002	-0.678	77.71
44	0.007	0.818	28.75	0.001	0.791	34.46	-0.002	-0.729	75.83	-0.003	-0.686	76.91
45	0.006	0.780	45.94	0.003	0.791	35.38	-0.002	-0.690	76.30	-0.001	-0.719	74.51
46	0.002	0.820	31.01	0.004	0.806	40.56	-0.003	-0.731	75.71	-0.000	-0.702	77.66
47	0.002	0.822	36.23	0.002	0.820	50.77	-0.001	-0.721	74.75	-0.001	-0.681	76.78
48	0.003	0.792	43.31	0.000	0.827	45.05	-0.002	-0.689	75.10	-0.002	-0.743	75.50
49	0.007	0.817	48.44	0.004	0.815	51.59	-0.002	-0.731	73.90	-0.001	-0.738	78.67
50	0.002	0.821	40.21	0.001	0.781	50.44	-0.002	-0.713	77.62	-0.002	-0.718	76.93
51	0.003	0.815	28.99	0.000	0.807	35.55	-0.000	-0.681	74.36	-0.002	-0.709	75.52
52	0.002	0.825	32.22	0.006	0.820	45.34	-0.001	-0.720	78.05	-0.000	-0.699	77.60
53	0.004	0.783	37.98	0.003	0.782	38.23	-0.001	-0.720	75.03	-0.003	-0.726	77.31
54	0.003	0.794	44.00	0.002	0.787	50.49	-0.003	-0.757	73.65	-0.002	-0.756	77.74

SeCoS Corporation

High Temperature Reverse Bias Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150 ± 5℃, 80%VR, T = 1000 hrs

Test Date: 2020.04.06 ~ 2020.05.19

Test Standard : JESD22 STANDARD Method-A108

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.004	0.789	30.57	0.002	0.807	40.07	-0.003	-0.758	77.38	-0.002	-0.725	78.42
56	0.002	0.811	45.85	0.002	0.814	48.61	-0.002	-0.711	74.74	-0.001	-0.674	77.38
57	0.004	0.817	49.52	0.006	0.792	41.56	-0.001	-0.721	75.20	-0.001	-0.661	77.18
58	0.000	0.797	40.29	0.001	0.803	48.67	-0.003	-0.663	74.38	-0.001	-0.763	78.31
59	0.006	0.821	50.77	0.006	0.819	33.19	-0.003	-0.750	74.37	-0.001	-0.665	74.16
60	0.003	0.807	30.88	0.003	0.793	48.48	-0.002	-0.700	74.57	-0.000	-0.758	74.57
61	0.006	0.816	31.75	0.000	0.793	32.90	-0.002	-0.707	78.21	-0.001	-0.731	74.40
62	0.001	0.823	38.95	0.001	0.802	38.66	-0.003	-0.669	73.55	-0.002	-0.681	76.99
63	0.002	0.785	32.21	0.006	0.827	50.31	-0.001	-0.702	77.23	-0.002	-0.754	75.23
64	0.006	0.810	32.43	0.006	0.825	42.49	-0.001	-0.695	78.21	-0.002	-0.674	74.94
65	0.003	0.779	39.67	0.003	0.822	42.66	-0.001	-0.734	76.35	-0.001	-0.689	76.73
66	0.004	0.802	51.24	0.004	0.830	36.93	-0.002	-0.713	78.13	-0.000	-0.756	76.83
67	0.002	0.785	41.45	0.007	0.807	41.83	-0.002	-0.713	77.83	-0.000	-0.748	75.70
68	0.006	0.791	30.74	0.006	0.795	38.70	-0.003	-0.665	75.10	-0.002	-0.738	78.30
69	0.002	0.826	44.20	0.001	0.788	29.35	-0.002	-0.678	73.81	-0.002	-0.745	75.66
70	0.002	0.818	38.81	0.001	0.829	47.22	-0.002	-0.675	74.37	-0.001	-0.693	77.17
71	0.004	0.830	49.44	0.001	0.788	33.81	-0.002	-0.724	77.44	-0.003	-0.741	74.74
72	0.001	0.812	43.32	0.001	0.794	47.81	-0.002	-0.682	78.69	-0.002	-0.735	74.55
73	0.002	0.787	29.60	0.007	0.786	37.09	-0.001	-0.741	77.87	-0.001	-0.698	75.77
74	0.007	0.809	42.10	0.001	0.826	44.19	-0.000	-0.732	74.11	-0.002	-0.716	78.22
75	0.003	0.796	31.51	0.007	0.820	47.01	-0.003	-0.666	78.42	-0.003	-0.756	76.46
76	0.003	0.799	47.93	0.005	0.792	43.58	-0.001	-0.705	76.87	-0.002	-0.679	73.96
77	0.006	0.828	48.33	0.004	0.819	38.23	-0.000	-0.694	75.86	-0.002	-0.742	75.45

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150℃, 1000Hrs

Test Date: 2020.04.06 ~ 2020.05.19

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.006	0.828	46.84	0.005	0.783	33.27	-0.002	-0.743	77.99	-0.003	-0.737	78.20
2	0.002	0.799	42.88	0.004	0.798	51.27	-0.003	-0.675	74.31	-0.001	-0.762	74.95
3	0.001	0.811	38.70	0.002	0.822	42.47	-0.001	-0.691	76.42	-0.002	-0.726	74.18
4	0.006	0.779	48.95	0.007	0.784	46.69	-0.001	-0.675	73.63	-0.001	-0.763	77.29
5	0.005	0.811	42.47	0.006	0.803	30.58	-0.002	-0.707	73.98	-0.003	-0.723	73.58
6	0.006	0.808	33.32	0.003	0.829	46.72	-0.001	-0.743	75.34	-0.000	-0.749	75.73
7	0.005	0.820	40.78	0.006	0.784	46.59	-0.002	-0.719	75.23	-0.000	-0.703	76.90
8	0.007	0.807	36.63	0.001	0.825	29.02	-0.001	-0.678	74.95	-0.000	-0.712	77.28
9	0.003	0.806	43.13	0.000	0.790	38.09	-0.002	-0.694	75.71	-0.001	-0.753	78.48
10	0.007	0.794	47.67	0.006	0.797	36.83	-0.001	-0.724	78.61	-0.001	-0.754	77.78
11	0.003	0.801	49.12	0.006	0.809	42.15	-0.000	-0.744	76.20	-0.000	-0.697	75.55
12	0.003	0.791	36.79	0.005	0.810	44.49	-0.001	-0.719	73.75	-0.000	-0.752	77.06
13	0.000	0.801	34.76	0.007	0.811	36.69	-0.003	-0.701	75.77	-0.001	-0.662	77.72
14	0.003	0.804	44.83	0.005	0.830	32.96	-0.001	-0.661	74.85	-0.001	-0.692	75.11
15	0.006	0.804	34.35	0.006	0.800	40.32	-0.002	-0.757	74.96	-0.003	-0.685	75.35
16	0.003	0.794	31.89	0.002	0.797	38.51	-0.000	-0.685	77.76	-0.001	-0.732	76.81
17	0.003	0.807	46.52	0.004	0.782	34.16	-0.002	-0.750	76.55	-0.000	-0.758	76.87
18	0.002	0.818	37.45	0.004	0.806	31.00	-0.001	-0.677	74.10	-0.003	-0.748	73.73
19	0.003	0.788	46.44	0.001	0.787	42.39	-0.003	-0.667	74.16	-0.003	-0.713	77.46
20	0.006	0.785	50.83	0.005	0.821	41.54	-0.002	-0.697	76.69	-0.000	-0.720	77.55
21	0.005	0.815	41.83	0.001	0.792	36.85	-0.002	-0.671	77.43	-0.002	-0.754	74.12
22	0.007	0.796	47.68	0.001	0.810	44.29	-0.003	-0.728	74.65	-0.001	-0.666	74.76
23	0.004	0.821	39.69	0.003	0.829	30.37	-0.002	-0.693	74.85	-0.001	-0.685	78.44
24	0.001	0.794	32.81	0.006	0.822	35.38	-0.001	-0.755	75.80	-0.000	-0.752	76.78
25	0.001	0.804	43.38	0.002	0.827	33.07	-0.003	-0.702	75.92	-0.001	-0.702	76.76
26	0.001	0.808	51.53	0.006	0.831	49.04	-0.000	-0.669	75.81	-0.000	-0.740	74.37
27	0.005	0.814	29.16	0.003	0.830	35.53	-0.001	-0.699	77.29	-0.001	-0.763	78.71

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150℃, 1000Hrs

Test Date: 2020.04.06 ~ 2020.05.19

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.000	0.782	38.45	0.004	0.799	34.70	-0.001	-0.695	74.91	-0.003	-0.750	74.75
29	0.007	0.786	44.26	0.004	0.797	37.48	-0.003	-0.708	73.55	-0.002	-0.712	77.16
30	0.005	0.804	38.92	0.001	0.788	31.01	-0.000	-0.713	75.28	-0.003	-0.748	74.29
31	0.001	0.781	35.51	0.004	0.828	47.47	-0.000	-0.715	77.40	-0.003	-0.717	75.66
32	0.003	0.782	47.60	0.001	0.808	43.18	-0.002	-0.674	76.04	-0.000	-0.705	74.07
33	0.004	0.788	44.61	0.002	0.823	29.86	-0.001	-0.739	75.80	-0.002	-0.733	74.74
34	0.002	0.814	44.92	0.005	0.828	38.89	-0.002	-0.741	73.83	-0.001	-0.701	74.75
35	0.005	0.791	48.50	0.002	0.801	30.55	-0.003	-0.682	77.11	-0.002	-0.663	77.63
36	0.005	0.778	48.01	0.006	0.820	34.79	-0.001	-0.669	76.19	-0.001	-0.708	76.72
37	0.003	0.801	49.52	0.007	0.814	50.26	-0.002	-0.670	77.31	-0.000	-0.753	76.10
38	0.001	0.787	47.13	0.001	0.830	50.15	-0.003	-0.721	74.27	-0.002	-0.658	76.66
39	0.007	0.826	33.52	0.003	0.797	39.45	-0.003	-0.720	75.14	-0.001	-0.708	75.72
40	0.003	0.795	44.33	0.004	0.789	46.97	-0.002	-0.675	76.15	-0.002	-0.745	78.41
41	0.005	0.820	29.46	0.002	0.812	29.69	-0.000	-0.724	78.40	-0.000	-0.697	74.11
42	0.003	0.809	37.14	0.000	0.800	29.66	-0.001	-0.745	75.17	-0.002	-0.748	75.44
43	0.001	0.780	49.66	0.003	0.785	30.44	-0.000	-0.660	77.00	-0.000	-0.747	74.10
44	0.004	0.802	44.44	0.007	0.816	41.12	-0.001	-0.741	75.60	-0.001	-0.760	75.20
45	0.001	0.822	44.76	0.004	0.796	31.65	-0.003	-0.737	73.85	-0.001	-0.744	77.85
46	0.002	0.802	34.08	0.004	0.806	50.78	-0.001	-0.731	74.59	-0.002	-0.714	76.66
47	0.002	0.824	45.84	0.006	0.827	50.61	-0.002	-0.738	74.56	-0.001	-0.688	75.44
48	0.000	0.780	38.21	0.001	0.804	32.71	-0.001	-0.693	76.44	-0.003	-0.741	74.19
49	0.006	0.779	47.64	0.000	0.817	36.61	-0.002	-0.737	75.86	-0.001	-0.669	73.96
50	0.003	0.802	51.04	0.005	0.783	37.47	-0.000	-0.708	77.00	-0.003	-0.752	75.24
51	0.003	0.779	34.48	0.004	0.784	38.89	-0.002	-0.745	75.32	-0.000	-0.707	74.41
52	0.001	0.795	48.97	0.005	0.810	46.93	-0.001	-0.742	78.21	-0.003	-0.740	74.56
53	0.002	0.822	51.59	0.005	0.826	35.37	-0.001	-0.743	76.98	-0.003	-0.682	74.73
54	0.002	0.811	40.41	0.002	0.816	44.23	-0.001	-0.686	75.63	-0.002	-0.668	77.74

SeCoS Corporation

High Temperature Storage Life Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 150℃, 1000Hrs

Test Date: 2020.04.06 ~ 2020.05.19

Test Standard : JESD22 STANDARD Method-A103

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.007	0.812	50.37	0.006	0.796	40.13	-0.001	-0.711	75.99	-0.002	-0.666	74.56
56	0.000	0.782	32.72	0.005	0.813	43.30	-0.003	-0.711	77.71	-0.001	-0.751	77.32
57	0.001	0.814	44.92	0.006	0.797	34.53	-0.003	-0.750	74.63	-0.002	-0.735	73.72
58	0.006	0.831	45.37	0.002	0.806	47.13	-0.003	-0.664	75.21	-0.001	-0.686	74.98
59	0.001	0.788	33.99	0.007	0.789	50.52	-0.000	-0.692	78.24	-0.001	-0.745	74.97
60	0.001	0.784	40.61	0.005	0.795	49.32	-0.001	-0.707	74.25	-0.002	-0.742	75.65
61	0.004	0.812	37.99	0.002	0.829	29.36	-0.001	-0.676	77.33	-0.003	-0.698	76.33
62	0.003	0.795	33.67	0.002	0.799	36.67	-0.002	-0.673	74.76	-0.001	-0.756	75.73
63	0.001	0.822	39.46	0.001	0.816	49.34	-0.002	-0.740	74.01	-0.003	-0.670	74.35
64	0.004	0.787	47.34	0.001	0.813	39.88	-0.002	-0.726	74.16	-0.002	-0.742	74.00
65	0.001	0.825	44.48	0.002	0.801	32.98	-0.001	-0.667	74.41	-0.001	-0.684	76.49
66	0.006	0.793	30.26	0.001	0.809	48.62	-0.002	-0.740	77.92	-0.002	-0.738	75.77
67	0.002	0.809	33.27	0.005	0.824	31.56	-0.001	-0.691	74.95	-0.002	-0.666	75.60
68	0.002	0.800	33.84	0.002	0.783	33.36	-0.001	-0.693	73.89	-0.001	-0.728	73.71
69	0.002	0.823	50.02	0.001	0.781	40.33	-0.001	-0.710	75.66	-0.001	-0.761	77.00
70	0.003	0.801	35.36	0.006	0.784	49.87	-0.003	-0.706	74.03	-0.001	-0.763	77.27
71	0.004	0.807	51.53	0.002	0.821	37.19	-0.000	-0.681	78.64	-0.001	-0.685	78.42
72	0.004	0.819	40.50	0.003	0.807	28.67	-0.001	-0.761	76.12	-0.002	-0.723	74.30
73	0.001	0.789	40.14	0.004	0.821	42.37	-0.001	-0.707	76.12	-0.003	-0.674	77.77
74	0.006	0.792	32.68	0.003	0.814	42.06	-0.001	-0.673	77.76	-0.001	-0.723	75.41
75	0.001	0.817	36.49	0.006	0.792	33.54	-0.001	-0.756	73.65	-0.002	-0.707	78.13
76	0.001	0.794	42.17	0.000	0.797	40.43	-0.000	-0.751	77.60	-0.003	-0.726	76.57
77	0.001	0.818	28.82	0.002	0.788	43.27	-0.001	-0.676	77.76	-0.002	-0.725	77.46

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Pressure Cooker Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2020.04.06 ~ 2020.04.14

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.003	0.797	35.26	0.003	0.783	50.67	-0.002	-0.709	77.99	-0.001	-0.704	76.31
2	0.006	0.808	29.99	0.004	0.807	44.36	-0.002	-0.693	77.89	-0.002	-0.715	76.37
3	0.001	0.796	39.03	0.002	0.806	30.57	-0.001	-0.746	74.81	-0.000	-0.680	75.72
4	0.001	0.801	47.85	0.005	0.802	33.80	-0.000	-0.689	78.56	-0.000	-0.701	75.16
5	0.000	0.825	42.03	0.005	0.798	50.49	-0.002	-0.707	78.14	-0.003	-0.742	74.56
6	0.003	0.808	39.10	0.006	0.804	47.29	-0.002	-0.718	73.97	-0.000	-0.706	77.61
7	0.003	0.817	48.32	0.007	0.785	43.08	-0.000	-0.749	78.08	-0.001	-0.750	75.31
8	0.002	0.780	31.64	0.006	0.813	32.05	-0.003	-0.729	74.82	-0.002	-0.721	77.84
9	0.004	0.827	40.27	0.002	0.782	28.69	-0.003	-0.688	78.14	-0.002	-0.665	75.34
10	0.007	0.813	35.07	0.002	0.800	34.29	-0.002	-0.678	75.37	-0.003	-0.692	76.38
11	0.003	0.783	37.32	0.003	0.788	49.39	-0.002	-0.692	75.97	-0.002	-0.658	76.22
12	0.002	0.794	40.63	0.006	0.786	32.78	-0.002	-0.675	78.45	-0.002	-0.706	75.14
13	0.007	0.823	38.30	0.006	0.804	47.76	-0.003	-0.673	75.63	-0.000	-0.704	76.46
14	0.001	0.805	40.99	0.005	0.808	51.36	-0.000	-0.757	77.91	-0.002	-0.700	76.70
15	0.005	0.814	38.54	0.002	0.797	34.84	-0.001	-0.744	75.23	-0.001	-0.713	78.25
16	0.001	0.785	46.82	0.001	0.828	42.49	-0.002	-0.686	76.72	-0.002	-0.756	74.44
17	0.000	0.788	46.17	0.002	0.791	41.61	-0.001	-0.736	74.49	-0.003	-0.694	78.16
18	0.007	0.790	31.80	0.004	0.784	29.57	-0.003	-0.670	78.04	-0.002	-0.665	74.56
19	0.002	0.824	29.17	0.005	0.796	34.07	-0.002	-0.684	78.36	-0.000	-0.759	74.39
20	0.002	0.811	43.68	0.003	0.779	31.00	-0.002	-0.713	74.10	-0.000	-0.677	74.36
21	0.000	0.790	48.71	0.006	0.814	44.43	-0.001	-0.750	74.84	-0.003	-0.732	74.29
22	0.002	0.819	37.64	0.004	0.783	30.91	-0.000	-0.757	77.45	-0.003	-0.720	76.25
23	0.004	0.802	39.47	0.007	0.818	29.07	-0.000	-0.746	77.03	-0.002	-0.719	78.66
24	0.004	0.826	45.45	0.002	0.802	43.59	-0.003	-0.679	76.84	-0.002	-0.718	77.68
25	0.003	0.786	41.53	0.002	0.818	39.35	-0.002	-0.664	77.94	-0.001	-0.697	76.46
26	0.007	0.786	39.41	0.001	0.789	32.97	-0.001	-0.752	77.64	-0.001	-0.659	78.15
27	0.005	0.789	41.95	0.005	0.817	43.55	-0.002	-0.706	73.85	-0.002	-0.668	76.48

SeCoS Corporation

Pressure Cooker Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2020.04.06 ~ 2020.04.14

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.005	0.807	37.48	0.007	0.783	31.48	-0.002	-0.721	78.04	-0.002	-0.761	73.84
29	0.002	0.801	34.88	0.007	0.821	49.53	-0.001	-0.668	74.16	-0.002	-0.659	74.29
30	0.003	0.818	36.14	0.002	0.828	33.73	-0.002	-0.682	74.75	-0.001	-0.745	74.38
31	0.006	0.800	29.99	0.002	0.801	37.37	-0.001	-0.690	76.04	-0.000	-0.740	74.27
32	0.002	0.802	44.90	0.004	0.825	46.95	-0.001	-0.736	77.26	-0.003	-0.660	74.40
33	0.002	0.823	33.62	0.001	0.808	38.39	-0.002	-0.744	76.23	-0.002	-0.724	74.65
34	0.001	0.790	28.77	0.004	0.781	29.53	-0.002	-0.673	74.20	-0.002	-0.719	75.25
35	0.001	0.819	47.43	0.005	0.814	30.03	-0.001	-0.754	74.94	-0.002	-0.751	75.66
36	0.006	0.797	38.40	0.007	0.811	47.76	-0.001	-0.714	75.88	-0.001	-0.755	77.99
37	0.004	0.806	33.78	0.003	0.826	43.63	-0.002	-0.695	76.89	-0.001	-0.668	74.63
38	0.002	0.815	43.62	0.001	0.780	32.82	-0.000	-0.729	73.72	-0.000	-0.756	77.18
39	0.004	0.819	42.00	0.004	0.778	48.46	-0.002	-0.728	73.61	-0.003	-0.677	73.84
40	0.004	0.822	44.32	0.003	0.811	33.92	-0.003	-0.683	75.50	-0.003	-0.664	74.75
41	0.004	0.825	48.58	0.004	0.803	49.51	-0.000	-0.703	73.60	-0.002	-0.720	77.69
42	0.006	0.827	39.96	0.003	0.787	49.03	-0.001	-0.737	76.79	-0.001	-0.752	78.63
43	0.001	0.817	32.59	0.000	0.808	38.70	-0.002	-0.723	74.00	-0.002	-0.699	74.02
44	0.003	0.824	41.84	0.004	0.778	44.78	-0.001	-0.675	76.62	-0.000	-0.677	76.95
45	0.001	0.793	36.61	0.005	0.830	32.60	-0.001	-0.718	74.29	-0.001	-0.690	74.31
46	0.006	0.802	29.30	0.003	0.783	44.47	-0.001	-0.726	75.78	-0.002	-0.727	75.50
47	0.006	0.808	46.35	0.006	0.821	36.49	-0.003	-0.755	74.17	-0.002	-0.701	78.34
48	0.002	0.810	47.35	0.007	0.817	28.81	-0.001	-0.759	78.57	-0.001	-0.683	76.37
49	0.000	0.796	32.04	0.007	0.821	50.08	-0.001	-0.705	74.60	-0.001	-0.751	74.32
50	0.002	0.788	39.71	0.002	0.806	46.51	-0.002	-0.721	77.65	-0.002	-0.673	76.45
51	0.007	0.790	51.53	0.002	0.790	31.78	-0.002	-0.690	77.97	-0.003	-0.662	73.87
52	0.003	0.829	36.69	0.003	0.782	35.94	-0.002	-0.730	74.06	-0.002	-0.674	75.19
53	0.001	0.799	31.95	0.007	0.822	36.62	-0.000	-0.747	76.86	-0.001	-0.740	75.91
54	0.002	0.814	39.60	0.007	0.786	29.32	-0.000	-0.760	74.00	-0.001	-0.763	74.98

SeCoS Corporation

Pressure Cooker Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)

P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 121℃, 100%RH, 29.7PSIG, 168Hrs

Test Date: 2020.04.06 ~ 2020.04.14

Test Standard : JESD22 STANDARD Method-A102

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.003	0.830	38.80	0.004	0.801	47.86	-0.002	-0.683	78.54	-0.001	-0.700	74.62
56	0.001	0.827	42.87	0.005	0.817	35.73	-0.001	-0.752	76.84	-0.003	-0.743	78.68
57	0.005	0.822	38.80	0.003	0.779	46.89	-0.001	-0.727	75.38	-0.002	-0.740	76.98
58	0.003	0.787	45.75	0.003	0.825	42.81	-0.002	-0.658	74.13	-0.003	-0.661	75.38
59	0.004	0.781	47.78	0.003	0.813	38.76	-0.000	-0.730	76.39	-0.001	-0.709	75.37
60	0.003	0.797	29.36	0.001	0.790	46.38	-0.000	-0.669	75.22	-0.002	-0.741	74.77
61	0.001	0.823	28.84	0.006	0.779	40.00	-0.002	-0.694	74.20	-0.002	-0.702	76.95
62	0.004	0.823	48.89	0.004	0.821	37.65	-0.002	-0.739	78.69	-0.001	-0.666	75.84
63	0.001	0.788	39.49	0.005	0.801	41.13	-0.003	-0.671	73.94	-0.001	-0.732	74.78
64	0.004	0.828	38.62	0.003	0.806	37.02	-0.001	-0.743	76.02	-0.001	-0.682	74.51
65	0.004	0.825	44.76	0.000	0.802	44.03	-0.003	-0.740	78.53	-0.000	-0.695	78.71
66	0.005	0.780	51.52	0.005	0.807	42.08	-0.003	-0.709	75.24	-0.001	-0.734	75.97
67	0.003	0.830	45.56	0.004	0.782	51.33	-0.003	-0.698	77.31	-0.001	-0.701	77.45
68	0.001	0.781	37.94	0.002	0.820	36.72	-0.002	-0.682	78.00	-0.003	-0.747	74.94
69	0.005	0.827	49.57	0.005	0.795	28.97	-0.003	-0.706	78.65	-0.002	-0.703	76.51
70	0.003	0.809	32.85	0.004	0.813	49.95	-0.002	-0.721	73.87	-0.003	-0.670	74.71
71	0.002	0.792	50.89	0.002	0.819	33.33	-0.002	-0.693	77.68	-0.001	-0.761	74.17
72	0.005	0.784	49.13	0.005	0.779	39.80	-0.002	-0.744	78.60	-0.000	-0.750	76.65
73	0.003	0.807	34.22	0.001	0.799	41.84	-0.002	-0.674	75.84	-0.001	-0.721	75.67
74	0.006	0.795	31.16	0.006	0.822	41.44	-0.003	-0.706	74.93	-0.002	-0.665	74.54
75	0.002	0.826	31.97	0.003	0.807	37.32	-0.001	-0.716	76.66	-0.001	-0.688	77.19
76	0.005	0.779	48.16	0.004	0.783	37.83	-0.001	-0.686	75.25	-0.000	-0.735	76.28
77	0.007	0.783	42.92	0.002	0.825	39.62	-0.000	-0.685	75.03	-0.001	-0.712	73.57

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Temperature Cycle Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle

Test Date: 2020.04.07 ~ 2020.05.29

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.005	0.792	31.32	0.005	0.812	48.40	-0.003	-0.732	76.23	-0.001	-0.754	76.38
2	0.006	0.805	51.34	0.005	0.817	38.79	-0.002	-0.677	75.64	-0.001	-0.736	77.29
3	0.002	0.812	44.50	0.003	0.805	51.20	-0.002	-0.704	74.51	-0.001	-0.696	75.44
4	0.006	0.779	31.44	0.005	0.794	42.94	-0.002	-0.738	74.56	-0.000	-0.708	78.42
5	0.005	0.781	33.62	0.004	0.783	39.31	-0.003	-0.737	75.08	-0.001	-0.735	75.40
6	0.004	0.797	41.87	0.005	0.812	46.93	-0.002	-0.660	78.46	-0.000	-0.747	74.26
7	0.001	0.827	47.25	0.005	0.810	50.49	-0.003	-0.703	75.34	-0.001	-0.714	77.42
8	0.005	0.807	36.94	0.006	0.829	38.92	-0.001	-0.708	74.95	-0.002	-0.700	74.46
9	0.003	0.792	50.03	0.002	0.802	50.95	-0.002	-0.685	75.29	-0.003	-0.762	77.01
10	0.004	0.814	48.30	0.001	0.826	46.07	-0.002	-0.737	76.49	-0.000	-0.739	77.69
11	0.000	0.810	33.50	0.000	0.817	33.66	-0.002	-0.689	74.77	-0.003	-0.740	78.38
12	0.006	0.788	51.71	0.000	0.797	50.82	-0.000	-0.755	74.40	-0.001	-0.705	74.71
13	0.005	0.784	32.70	0.001	0.781	37.19	-0.002	-0.715	73.84	-0.002	-0.666	77.79
14	0.002	0.830	38.60	0.005	0.825	40.30	-0.002	-0.679	76.08	-0.001	-0.694	76.93
15	0.003	0.814	36.83	0.005	0.790	51.69	-0.003	-0.681	73.82	-0.002	-0.687	77.69
16	0.004	0.813	47.91	0.005	0.790	42.71	-0.001	-0.716	77.81	-0.002	-0.695	77.66
17	0.003	0.817	43.44	0.006	0.804	29.07	-0.001	-0.682	78.28	-0.003	-0.710	74.32
18	0.000	0.827	36.69	0.005	0.809	38.14	-0.002	-0.745	77.60	-0.000	-0.716	77.06
19	0.003	0.811	33.04	0.006	0.824	35.40	-0.001	-0.742	76.83	-0.000	-0.686	77.87
20	0.002	0.812	32.03	0.005	0.791	35.67	-0.001	-0.665	75.92	-0.003	-0.662	75.77
21	0.004	0.816	30.29	0.001	0.827	30.64	-0.002	-0.690	74.03	-0.003	-0.740	78.07
22	0.005	0.821	28.68	0.005	0.828	34.21	-0.001	-0.696	78.03	-0.002	-0.760	75.30
23	0.002	0.830	44.41	0.005	0.830	28.95	-0.001	-0.730	74.40	-0.003	-0.752	78.18
24	0.001	0.810	46.70	0.006	0.803	38.72	-0.003	-0.715	73.84	-0.002	-0.729	77.32
25	0.002	0.831	29.69	0.006	0.810	41.68	-0.000	-0.725	76.51	-0.002	-0.716	77.13
26	0.005	0.800	35.77	0.000	0.798	43.48	-0.001	-0.689	75.15	-0.001	-0.663	76.50
27	0.004	0.831	44.34	0.004	0.785	36.35	-0.001	-0.744	76.47	-0.000	-0.666	74.96

SeCoS Corporation

Temperature Cycle Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle

Test Date: 2020.04.07 ~ 2020.05.29

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.006	0.803	45.57	0.006	0.789	39.90	-0.002	-0.739	74.41	-0.001	-0.680	77.13
29	0.005	0.828	48.42	0.004	0.783	48.57	-0.001	-0.684	76.30	-0.003	-0.663	78.51
30	0.002	0.805	40.26	0.002	0.786	30.14	-0.003	-0.671	73.54	-0.001	-0.688	77.84
31	0.002	0.809	37.53	0.007	0.809	35.17	-0.001	-0.688	73.81	-0.003	-0.682	76.49
32	0.004	0.825	39.89	0.001	0.789	33.50	-0.002	-0.743	76.10	-0.003	-0.758	74.18
33	0.005	0.789	36.10	0.003	0.811	42.03	-0.000	-0.745	74.37	-0.000	-0.749	73.58
34	0.000	0.790	28.98	0.002	0.801	29.05	-0.002	-0.663	76.73	-0.001	-0.730	74.87
35	0.003	0.817	49.12	0.005	0.792	45.14	-0.002	-0.687	76.96	-0.002	-0.666	75.66
36	0.006	0.814	34.90	0.005	0.788	47.08	-0.002	-0.717	75.60	-0.001	-0.750	74.08
37	0.000	0.807	46.90	0.002	0.787	36.17	-0.002	-0.684	78.03	-0.000	-0.675	78.54
38	0.000	0.790	48.53	0.006	0.815	41.75	-0.002	-0.678	76.75	-0.002	-0.671	78.67
39	0.007	0.786	50.04	0.006	0.808	51.26	-0.001	-0.743	76.98	-0.002	-0.701	75.17
40	0.007	0.782	47.49	0.007	0.812	31.67	-0.002	-0.690	78.48	-0.001	-0.732	74.42
41	0.004	0.828	45.21	0.006	0.807	31.67	-0.003	-0.743	77.19	-0.002	-0.694	75.05
42	0.003	0.798	34.63	0.004	0.826	31.43	-0.003	-0.758	75.24	-0.001	-0.713	74.08
43	0.005	0.807	40.14	0.005	0.780	35.63	-0.003	-0.679	73.76	-0.003	-0.747	74.72
44	0.002	0.802	45.48	0.002	0.795	33.12	-0.001	-0.705	74.55	-0.002	-0.717	77.72
45	0.005	0.800	48.90	0.004	0.826	36.56	-0.001	-0.695	73.80	-0.003	-0.662	74.70
46	0.002	0.820	51.50	0.001	0.791	34.18	-0.001	-0.726	76.36	-0.002	-0.734	78.41
47	0.003	0.806	30.30	0.004	0.800	34.67	-0.003	-0.690	74.62	-0.000	-0.758	78.69
48	0.007	0.779	47.43	0.003	0.811	30.05	-0.002	-0.703	78.68	-0.000	-0.722	78.59
49	0.003	0.797	33.29	0.003	0.822	29.20	-0.003	-0.747	75.41	-0.002	-0.704	77.99
50	0.007	0.831	48.17	0.004	0.782	41.93	-0.002	-0.730	74.97	-0.001	-0.710	77.02
51	0.001	0.802	32.95	0.001	0.789	29.04	-0.003	-0.685	76.93	-0.001	-0.704	77.36
52	0.000	0.805	51.26	0.004	0.827	47.39	-0.001	-0.692	76.24	-0.003	-0.709	73.66
53	0.005	0.786	40.27	0.007	0.806	36.75	-0.000	-0.662	78.69	-0.002	-0.746	75.55
54	0.005	0.790	29.40	0.007	0.800	32.17	-0.003	-0.754	77.48	-0.003	-0.725	78.10

SeCoS Corporation

Temperature Cycle Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: -55℃/30min, 150℃/30min, for1000 Cycle

Test Date: 2020.04.07 ~ 2020.05.29

Test Standard : JESD22 STANDARD Method-A104

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.005	0.804	34.82	0.003	0.795	45.17	-0.002	-0.694	78.19	-0.000	-0.686	78.41
56	0.004	0.811	40.97	0.002	0.829	39.74	-0.001	-0.695	74.12	-0.000	-0.737	75.91
57	0.002	0.790	32.70	0.002	0.780	43.01	-0.002	-0.729	77.47	-0.002	-0.711	76.88
58	0.006	0.810	40.19	0.002	0.811	51.12	-0.001	-0.668	74.81	-0.002	-0.671	73.59
59	0.001	0.801	29.24	0.004	0.812	38.28	-0.003	-0.730	76.60	-0.002	-0.735	74.22
60	0.004	0.791	48.64	0.001	0.821	35.32	-0.002	-0.702	77.75	-0.002	-0.735	74.99
61	0.005	0.781	45.28	0.002	0.804	40.34	-0.002	-0.726	76.06	-0.003	-0.749	76.57
62	0.004	0.823	49.14	0.004	0.796	50.17	-0.003	-0.724	77.55	-0.003	-0.672	76.42
63	0.007	0.797	50.05	0.003	0.779	51.52	-0.001	-0.709	77.63	-0.002	-0.697	74.38
64	0.003	0.786	37.08	0.003	0.810	29.54	-0.003	-0.728	77.41	-0.002	-0.700	75.80
65	0.005	0.825	41.97	0.003	0.794	38.23	-0.001	-0.748	78.14	-0.002	-0.687	75.28
66	0.005	0.803	32.37	0.005	0.820	47.49	-0.002	-0.718	75.35	-0.000	-0.752	74.96
67	0.004	0.802	39.06	0.004	0.819	39.43	-0.003	-0.758	74.48	-0.002	-0.723	75.87
68	0.006	0.784	40.04	0.005	0.815	45.09	-0.003	-0.684	75.92	-0.001	-0.697	74.41
69	0.004	0.831	44.23	0.006	0.818	48.04	-0.000	-0.741	75.22	-0.002	-0.719	77.10
70	0.004	0.824	39.43	0.002	0.804	49.58	-0.002	-0.669	76.63	-0.001	-0.661	75.15
71	0.006	0.795	32.52	0.002	0.779	31.13	-0.002	-0.719	76.77	-0.002	-0.727	77.57
72	0.005	0.800	41.61	0.001	0.822	43.23	-0.000	-0.723	77.73	-0.001	-0.733	73.78
73	0.005	0.822	34.39	0.007	0.817	35.99	-0.002	-0.677	75.05	-0.001	-0.746	75.44
74	0.003	0.815	40.78	0.000	0.801	38.83	-0.001	-0.763	76.30	-0.002	-0.667	76.94
75	0.004	0.807	48.81	0.001	0.813	31.01	-0.001	-0.722	75.37	-0.000	-0.709	78.30
76	0.003	0.820	35.62	0.001	0.783	31.57	-0.003	-0.760	78.01	-0.002	-0.709	75.00
77	0.002	0.809	47.15	0.003	0.824	46.59	-0.000	-0.751	78.21	-0.001	-0.762	76.54

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 1000Hrs

Test Date: 2020.04.14 ~ 2020.05.27

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.005	0.807	43.91	0.004	0.781	34.47	-0.000	-0.698	77.70	-0.001	-0.759	78.35
2	0.000	0.805	47.15	0.004	0.809	37.84	-0.002	-0.728	74.56	-0.001	-0.740	74.56
3	0.005	0.798	36.97	0.001	0.820	37.56	-0.002	-0.731	78.02	-0.000	-0.723	74.78
4	0.005	0.808	45.62	0.002	0.791	33.08	-0.000	-0.740	73.90	-0.002	-0.658	76.97
5	0.002	0.812	43.39	0.001	0.812	29.63	-0.003	-0.666	76.15	-0.001	-0.759	74.24
6	0.001	0.789	46.43	0.002	0.821	33.69	-0.002	-0.719	78.55	-0.002	-0.711	76.87
7	0.006	0.793	46.78	0.003	0.825	44.94	-0.002	-0.726	75.59	-0.001	-0.740	77.73
8	0.004	0.805	42.21	0.004	0.804	41.42	-0.001	-0.663	77.19	-0.002	-0.755	78.47
9	0.005	0.792	43.30	0.007	0.784	41.63	-0.002	-0.668	74.96	-0.001	-0.662	75.30
10	0.007	0.829	48.05	0.003	0.788	39.72	-0.001	-0.674	76.22	-0.002	-0.753	78.46
11	0.004	0.816	32.28	0.002	0.781	45.41	-0.002	-0.739	75.26	-0.001	-0.696	77.39
12	0.002	0.793	32.40	0.007	0.783	33.20	-0.003	-0.735	76.19	-0.001	-0.748	74.39
13	0.001	0.810	33.32	0.006	0.792	28.58	-0.002	-0.687	74.67	-0.002	-0.666	78.49
14	0.006	0.799	33.32	0.006	0.796	50.20	-0.003	-0.744	74.89	-0.001	-0.713	73.84
15	0.006	0.828	35.14	0.002	0.818	49.00	-0.002	-0.707	77.43	-0.002	-0.685	75.95
16	0.005	0.781	38.54	0.007	0.819	30.72	-0.001	-0.712	74.33	-0.001	-0.663	73.59
17	0.001	0.795	32.33	0.004	0.809	38.27	-0.001	-0.719	74.21	-0.000	-0.739	78.42
18	0.006	0.812	38.93	0.002	0.820	40.60	-0.001	-0.661	73.67	-0.001	-0.696	74.19
19	0.001	0.779	43.35	0.001	0.794	39.46	-0.002	-0.695	75.00	-0.003	-0.725	76.47
20	0.000	0.828	33.38	0.003	0.823	29.69	-0.000	-0.666	75.03	-0.001	-0.749	75.93
21	0.003	0.779	49.66	0.002	0.825	28.77	-0.002	-0.714	77.59	-0.001	-0.743	78.29
22	0.003	0.805	39.53	0.002	0.784	51.20	-0.001	-0.755	73.57	-0.002	-0.669	78.08
23	0.002	0.808	34.73	0.006	0.829	37.47	-0.002	-0.663	77.72	-0.003	-0.678	76.96
24	0.005	0.786	41.86	0.001	0.826	44.46	-0.000	-0.661	78.09	-0.002	-0.680	75.77
25	0.002	0.818	41.54	0.002	0.808	37.17	-0.001	-0.723	77.21	-0.002	-0.663	76.69
26	0.007	0.792	50.82	0.004	0.805	39.53	-0.002	-0.699	77.53	-0.001	-0.659	75.92
27	0.003	0.809	41.25	0.007	0.787	45.18	-0.002	-0.707	78.45	-0.003	-0.764	77.53

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 1000Hrs

Test Date: 2020.04.14 ~ 2020.05.27

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.007	0.821	29.25	0.004	0.784	41.60	-0.001	-0.728	77.17	-0.002	-0.745	78.02
29	0.006	0.828	49.79	0.006	0.801	35.72	-0.000	-0.700	74.52	-0.002	-0.725	75.41
30	0.006	0.778	41.94	0.003	0.800	43.79	-0.001	-0.661	77.37	-0.001	-0.666	76.81
31	0.001	0.814	37.95	0.005	0.809	51.73	-0.001	-0.664	77.73	-0.002	-0.738	76.07
32	0.002	0.817	45.11	0.004	0.828	48.87	-0.001	-0.743	75.54	-0.001	-0.730	74.07
33	0.002	0.785	46.95	0.000	0.810	43.92	-0.000	-0.748	76.28	-0.000	-0.735	74.45
34	0.007	0.821	40.09	0.003	0.803	39.61	-0.001	-0.715	77.03	-0.002	-0.738	73.55
35	0.003	0.790	29.16	0.002	0.817	28.76	-0.000	-0.720	77.23	-0.002	-0.732	74.22
36	0.001	0.802	46.89	0.003	0.810	51.30	-0.003	-0.742	78.29	-0.002	-0.683	74.95
37	0.006	0.830	30.77	0.006	0.794	31.76	-0.001	-0.739	73.65	-0.003	-0.712	78.57
38	0.005	0.817	33.80	0.006	0.802	42.10	-0.002	-0.741	75.12	-0.003	-0.668	75.39
39	0.006	0.801	48.96	0.004	0.826	48.02	-0.001	-0.752	75.73	-0.001	-0.700	78.36
40	0.005	0.811	32.15	0.003	0.824	34.60	-0.001	-0.697	75.89	-0.000	-0.746	76.61
41	0.002	0.794	45.51	0.001	0.793	40.21	-0.001	-0.712	77.62	-0.002	-0.722	76.74
42	0.000	0.816	51.16	0.003	0.785	51.70	-0.001	-0.734	78.24	-0.000	-0.742	75.31
43	0.006	0.814	32.91	0.002	0.818	47.12	-0.001	-0.741	78.70	-0.001	-0.755	75.69
44	0.005	0.785	35.80	0.001	0.823	46.03	-0.001	-0.744	73.56	-0.000	-0.696	73.96
45	0.001	0.816	39.95	0.006	0.787	39.11	-0.001	-0.686	76.02	-0.002	-0.725	75.64
46	0.005	0.810	49.03	0.005	0.808	29.48	-0.002	-0.687	74.43	-0.000	-0.755	75.84
47	0.005	0.783	40.50	0.003	0.826	35.91	-0.002	-0.763	77.85	-0.002	-0.720	78.33
48	0.005	0.784	36.72	0.002	0.786	51.58	-0.000	-0.758	73.68	-0.002	-0.750	77.48
49	0.002	0.825	39.87	0.003	0.794	30.24	-0.001	-0.671	76.44	-0.001	-0.683	76.05
50	0.005	0.820	34.61	0.004	0.789	46.88	-0.001	-0.684	77.04	-0.003	-0.734	73.54
51	0.000	0.803	34.33	0.005	0.810	30.88	-0.002	-0.707	75.12	-0.002	-0.727	73.68
52	0.005	0.825	39.45	0.002	0.822	30.60	-0.003	-0.738	76.47	-0.002	-0.697	75.12
53	0.000	0.801	45.17	0.004	0.814	50.12	-0.002	-0.751	76.73	-0.003	-0.667	78.31
54	0.003	0.797	39.11	0.002	0.784	45.76	-0.001	-0.745	76.82	-0.001	-0.658	77.75

SeCoS Corporation

High Temperature High Humidity Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 1000Hrs

Test Date: 2020.04.14 ~ 2020.05.27

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.004	0.827	42.00	0.002	0.826	37.76	-0.003	-0.734	76.76	-0.001	-0.690	77.67
56	0.003	0.827	42.81	0.001	0.831	36.22	-0.002	-0.709	74.63	-0.002	-0.740	75.43
57	0.001	0.798	46.28	0.002	0.786	50.41	-0.003	-0.754	76.16	-0.003	-0.682	73.66
58	0.002	0.819	51.35	0.006	0.823	39.58	-0.001	-0.670	74.91	-0.002	-0.737	75.56
59	0.003	0.807	50.49	0.006	0.816	35.47	-0.003	-0.702	75.93	-0.000	-0.699	77.87
60	0.004	0.784	49.49	0.006	0.791	51.15	-0.002	-0.741	76.17	-0.002	-0.687	75.73
61	0.006	0.818	47.23	0.006	0.807	46.80	-0.000	-0.755	75.35	-0.000	-0.757	78.34
62	0.006	0.824	30.34	0.005	0.796	39.02	-0.001	-0.674	75.35	-0.003	-0.689	76.55
63	0.004	0.805	36.91	0.006	0.788	48.87	-0.000	-0.664	78.28	-0.001	-0.736	74.12
64	0.003	0.811	31.17	0.002	0.812	44.72	-0.001	-0.734	73.58	-0.001	-0.709	75.02
65	0.002	0.810	36.68	0.003	0.819	29.89	-0.003	-0.736	73.95	-0.002	-0.698	77.65
66	0.007	0.814	46.73	0.001	0.826	42.33	-0.002	-0.755	74.46	-0.002	-0.711	77.01
67	0.004	0.785	34.16	0.005	0.780	28.56	-0.000	-0.695	77.68	-0.002	-0.750	76.24
68	0.005	0.808	29.00	0.002	0.822	40.80	-0.001	-0.761	77.22	-0.001	-0.711	74.66
69	0.002	0.806	42.84	0.002	0.822	36.57	-0.002	-0.762	73.87	-0.001	-0.745	74.20
70	0.002	0.809	30.36	0.006	0.817	43.59	-0.001	-0.738	74.42	-0.000	-0.699	77.37
71	0.004	0.799	47.57	0.001	0.807	39.96	-0.003	-0.689	77.69	-0.002	-0.749	74.71
72	0.003	0.815	44.99	0.000	0.798	51.51	-0.000	-0.708	75.59	-0.001	-0.667	74.96
73	0.005	0.799	30.75	0.001	0.789	47.17	-0.000	-0.714	77.44	-0.001	-0.721	76.76
74	0.002	0.786	28.93	0.005	0.813	41.87	-0.003	-0.761	75.90	-0.001	-0.722	77.99
75	0.007	0.814	36.73	0.004	0.792	32.63	-0.002	-0.696	74.38	-0.002	-0.743	75.40
76	0.004	0.780	29.15	0.006	0.789	38.85	-0.001	-0.735	75.91	-0.002	-0.729	78.11
77	0.002	0.779	46.12	0.000	0.790	42.19	-0.000	-0.672	75.02	-0.000	-0.691	78.29

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs

Test Date: 2020.04.14 ~ 2020.05.27

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.005	0.813	44.08	0.005	0.802	30.11	-0.002	-0.754	78.16	-0.002	-0.716	77.38
2	0.005	0.807	31.47	0.005	0.830	36.32	-0.000	-0.681	74.70	-0.003	-0.763	76.00
3	0.001	0.812	51.05	0.003	0.789	40.27	-0.003	-0.679	77.86	-0.002	-0.727	77.71
4	0.001	0.816	30.50	0.002	0.792	51.41	-0.002	-0.698	74.18	-0.001	-0.668	78.40
5	0.003	0.795	43.20	0.006	0.822	41.79	-0.000	-0.743	76.18	-0.000	-0.759	76.53
6	0.003	0.823	44.88	0.005	0.810	42.51	-0.003	-0.725	76.57	-0.002	-0.684	77.03
7	0.003	0.807	43.77	0.005	0.825	48.95	-0.000	-0.754	73.91	-0.000	-0.714	74.73
8	0.004	0.785	38.86	0.001	0.826	46.27	-0.001	-0.674	75.61	-0.001	-0.706	73.66
9	0.006	0.813	31.18	0.004	0.793	39.88	-0.001	-0.678	75.95	-0.002	-0.727	77.24
10	0.006	0.788	40.15	0.004	0.811	45.02	-0.000	-0.684	76.20	-0.002	-0.761	75.89
11	0.006	0.785	49.39	0.006	0.827	32.03	-0.002	-0.677	75.62	-0.003	-0.746	74.81
12	0.003	0.811	38.14	0.006	0.819	37.08	-0.001	-0.736	75.10	-0.001	-0.717	75.50
13	0.005	0.794	46.57	0.001	0.810	30.43	-0.001	-0.761	76.56	-0.002	-0.730	73.55
14	0.001	0.792	37.58	0.000	0.825	29.34	-0.002	-0.686	74.27	-0.002	-0.673	74.29
15	0.006	0.778	40.77	0.002	0.793	38.71	-0.000	-0.713	74.97	-0.001	-0.722	74.33
16	0.001	0.794	44.26	0.005	0.781	34.18	-0.001	-0.755	75.85	-0.001	-0.683	75.54
17	0.005	0.811	40.92	0.001	0.811	39.86	-0.002	-0.659	78.62	-0.003	-0.723	76.71
18	0.003	0.785	35.97	0.005	0.779	38.32	-0.003	-0.688	73.67	-0.001	-0.751	75.90
19	0.002	0.827	30.81	0.004	0.787	32.71	-0.002	-0.684	78.47	-0.001	-0.685	75.12
20	0.002	0.809	29.57	0.001	0.795	48.94	-0.001	-0.701	75.46	-0.000	-0.725	77.80
21	0.002	0.810	34.43	0.002	0.829	36.19	-0.001	-0.659	74.93	-0.000	-0.762	73.73
22	0.004	0.794	36.79	0.006	0.784	51.33	-0.000	-0.715	75.88	-0.002	-0.704	77.15
23	0.001	0.806	42.54	0.002	0.807	29.25	-0.001	-0.679	73.71	-0.002	-0.659	74.63
24	0.004	0.819	40.83	0.001	0.798	47.22	-0.000	-0.757	74.63	-0.001	-0.710	75.53
25	0.000	0.814	37.19	0.002	0.791	50.02	-0.002	-0.756	76.48	-0.003	-0.716	76.02
26	0.006	0.787	42.10	0.007	0.823	37.11	-0.001	-0.670	75.92	-0.000	-0.694	73.64
27	0.005	0.782	33.62	0.004	0.793	44.65	-0.002	-0.759	76.77	-0.001	-0.672	74.35

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs

Test Date: 2020.04.14 ~ 2020.05.27

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.006	0.805	43.94	0.004	0.798	41.06	-0.001	-0.739	74.90	-0.001	-0.682	74.94
29	0.001	0.813	36.07	0.001	0.803	32.05	-0.003	-0.732	78.52	-0.001	-0.672	75.58
30	0.000	0.780	29.33	0.007	0.812	34.14	-0.002	-0.705	78.70	-0.002	-0.738	78.45
31	0.002	0.828	29.89	0.003	0.807	31.46	-0.001	-0.723	74.16	-0.002	-0.680	78.39
32	0.005	0.800	36.20	0.002	0.790	43.37	-0.001	-0.706	74.35	-0.002	-0.750	78.26
33	0.005	0.819	41.41	0.002	0.828	36.32	-0.000	-0.700	76.67	-0.003	-0.747	76.25
34	0.006	0.824	47.65	0.006	0.800	41.55	-0.001	-0.739	75.86	-0.003	-0.687	77.64
35	0.001	0.827	45.99	0.003	0.814	40.26	-0.001	-0.722	75.76	-0.002	-0.682	77.95
36	0.000	0.801	30.93	0.006	0.820	49.38	-0.000	-0.671	75.30	-0.002	-0.678	74.51
37	0.002	0.827	32.27	0.003	0.827	32.51	-0.000	-0.662	74.39	-0.002	-0.674	75.82
38	0.007	0.783	43.75	0.001	0.802	37.71	-0.002	-0.713	73.64	-0.001	-0.739	76.48
39	0.004	0.813	41.62	0.007	0.787	38.36	-0.002	-0.694	75.34	-0.000	-0.719	74.16
40	0.003	0.785	35.31	0.005	0.808	48.02	-0.000	-0.715	75.22	-0.001	-0.736	78.47
41	0.003	0.785	46.85	0.002	0.780	33.39	-0.003	-0.696	74.23	-0.001	-0.712	77.67
42	0.007	0.803	29.82	0.005	0.802	39.24	-0.001	-0.671	75.00	-0.003	-0.718	75.23
43	0.002	0.805	45.69	0.001	0.800	51.21	-0.002	-0.729	74.34	-0.002	-0.734	78.32
44	0.004	0.814	43.17	0.002	0.818	29.61	-0.003	-0.689	77.35	-0.002	-0.740	76.65
45	0.000	0.818	51.76	0.006	0.805	41.90	-0.002	-0.694	76.27	-0.002	-0.680	75.57
46	0.007	0.804	42.54	0.002	0.808	39.42	-0.002	-0.745	77.46	-0.001	-0.677	77.23
47	0.002	0.823	43.04	0.005	0.819	34.29	-0.001	-0.753	73.88	-0.002	-0.669	78.63
48	0.007	0.830	43.78	0.006	0.829	49.59	-0.002	-0.699	77.42	-0.002	-0.740	77.32
49	0.001	0.807	47.80	0.002	0.817	36.12	-0.001	-0.715	75.73	-0.002	-0.735	78.21
50	0.001	0.826	38.00	0.007	0.784	42.50	-0.001	-0.706	77.34	-0.001	-0.659	77.23
51	0.001	0.796	40.63	0.006	0.791	43.49	-0.002	-0.763	77.62	-0.003	-0.761	78.27
52	0.001	0.793	47.34	0.001	0.824	33.75	-0.001	-0.757	75.16	-0.001	-0.685	78.11
53	0.007	0.790	39.11	0.003	0.807	45.39	-0.001	-0.674	77.06	-0.001	-0.718	78.48
54	0.001	0.799	33.61	0.004	0.827	45.37	-0.002	-0.660	74.57	-0.002	-0.731	77.82

SeCoS Corporation

High Temper High Humidity Reverse Bies Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 85±2℃, 85±5%RH, 80%VR, 1000Hrs

Test Date: 2020.04.14 ~ 2020.05.27

Test Standard : JESD22 STANDARD Method-A101

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.005	0.818	45.09	0.006	0.788	30.83	-0.002	-0.715	76.77	-0.000	-0.759	77.10
56	0.006	0.810	49.11	0.000	0.785	34.44	-0.002	-0.729	74.00	-0.002	-0.735	76.41
57	0.000	0.809	50.39	0.007	0.786	36.85	-0.003	-0.725	74.91	-0.000	-0.691	78.22
58	0.007	0.787	31.87	0.005	0.820	33.75	-0.001	-0.728	75.54	-0.003	-0.739	74.57
59	0.005	0.813	31.54	0.002	0.780	43.50	-0.000	-0.738	77.21	-0.001	-0.708	73.68
60	0.004	0.817	33.97	0.004	0.788	43.35	-0.002	-0.690	74.92	-0.003	-0.696	77.92
61	0.006	0.786	36.00	0.007	0.803	39.35	-0.002	-0.716	76.56	-0.002	-0.673	74.39
62	0.005	0.811	30.57	0.006	0.820	41.43	-0.002	-0.761	76.36	-0.000	-0.761	77.45
63	0.004	0.791	48.88	0.002	0.782	35.84	-0.003	-0.713	74.91	-0.002	-0.726	74.42
64	0.002	0.789	29.77	0.004	0.791	46.78	-0.003	-0.709	73.86	-0.001	-0.745	73.57
65	0.006	0.817	43.51	0.004	0.810	46.93	-0.000	-0.752	78.50	-0.001	-0.698	74.51
66	0.002	0.794	35.11	0.005	0.806	35.03	-0.003	-0.667	74.51	-0.001	-0.688	77.77
67	0.003	0.790	51.17	0.006	0.827	42.65	-0.002	-0.692	75.82	-0.000	-0.762	75.61
68	0.004	0.803	34.49	0.001	0.803	30.61	-0.001	-0.693	75.29	-0.002	-0.728	78.58
69	0.005	0.817	47.71	0.002	0.808	30.40	-0.003	-0.759	74.15	-0.002	-0.733	77.81
70	0.005	0.788	32.26	0.006	0.794	30.29	-0.001	-0.682	77.69	-0.001	-0.735	75.42
71	0.004	0.803	36.17	0.005	0.829	48.24	-0.001	-0.673	78.51	-0.000	-0.707	78.16
72	0.001	0.828	51.18	0.005	0.784	47.24	-0.000	-0.681	77.67	-0.001	-0.710	78.32
73	0.002	0.804	35.08	0.001	0.815	46.34	-0.001	-0.683	77.10	-0.003	-0.750	76.09
74	0.004	0.819	36.03	0.005	0.822	32.14	-0.000	-0.666	76.38	-0.001	-0.711	76.87
75	0.005	0.798	44.11	0.005	0.815	34.78	-0.001	-0.689	75.28	-0.002	-0.672	77.09
76	0.001	0.782	47.77	0.006	0.807	32.90	-0.001	-0.743	75.48	-0.001	-0.759	77.21
77	0.004	0.785	41.50	0.007	0.796	29.94	-0.002	-0.706	76.71	-0.002	-0.754	78.64

Made By: King Huang

Approval: Peter Yang

SeCoS Corporation

Resistance to Solder Heat Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 245℃ ± 5℃, 5Sec

Test Date: 2020.05.28

Test Standard : JESD22 STANDARD Method-B106

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
1	0.001	0.812	48.19	0.005	0.820	41.63	-0.002	-0.707	73.58	-0.000	-0.685	77.34
2	0.005	0.790	51.26	0.002	0.818	44.71	-0.002	-0.730	73.71	-0.003	-0.736	78.36
3	0.000	0.813	37.96	0.001	0.787	51.82	-0.002	-0.728	78.13	-0.001	-0.680	76.88
4	0.005	0.820	50.48	0.007	0.781	33.65	-0.003	-0.730	73.78	-0.000	-0.745	75.93
5	0.004	0.785	49.44	0.001	0.802	29.94	-0.000	-0.669	73.55	-0.003	-0.664	76.43
6	0.005	0.793	45.27	0.001	0.811	45.88	-0.000	-0.716	73.86	-0.001	-0.677	73.60
7	0.000	0.788	34.49	0.006	0.825	40.70	-0.001	-0.719	76.41	-0.000	-0.682	76.31
8	0.006	0.783	30.78	0.001	0.810	46.89	-0.002	-0.713	73.72	-0.000	-0.699	73.73
9	0.000	0.821	33.57	0.005	0.826	42.15	-0.001	-0.690	77.02	-0.002	-0.718	74.92
10	0.002	0.788	36.11	0.000	0.814	42.32	-0.001	-0.761	77.64	-0.001	-0.738	75.87
11	0.003	0.817	39.59	0.004	0.797	32.12	-0.002	-0.669	76.72	-0.002	-0.658	76.92
12	0.003	0.806	49.67	0.006	0.812	33.81	-0.000	-0.749	77.25	-0.001	-0.673	73.60
13	0.003	0.816	38.83	0.004	0.794	49.01	-0.001	-0.754	77.59	-0.003	-0.661	74.68
14	0.006	0.821	46.70	0.005	0.806	51.07	-0.001	-0.764	75.50	-0.000	-0.698	74.66
15	0.001	0.816	31.39	0.006	0.792	30.19	-0.002	-0.721	75.79	-0.001	-0.661	75.60
16	0.006	0.794	45.43	0.002	0.827	35.80	-0.002	-0.711	78.55	-0.002	-0.744	74.14
17	0.005	0.786	44.71	0.001	0.810	28.80	-0.002	-0.755	76.44	-0.001	-0.687	78.52
18	0.006	0.830	32.40	0.000	0.792	37.94	-0.003	-0.668	73.73	-0.002	-0.670	76.30
19	0.002	0.806	36.20	0.000	0.828	32.85	-0.002	-0.751	75.71	-0.001	-0.746	76.73
20	0.006	0.789	34.25	0.001	0.798	46.33	-0.001	-0.732	78.33	-0.002	-0.683	73.62
21	0.004	0.817	49.62	0.000	0.795	46.81	-0.001	-0.663	76.26	-0.001	-0.761	75.38
22	0.005	0.802	46.64	0.006	0.802	44.26	-0.003	-0.706	78.13	-0.003	-0.676	76.81
23	0.004	0.784	49.73	0.001	0.828	39.98	-0.002	-0.719	77.12	-0.002	-0.696	73.57
24	0.001	0.830	46.67	0.001	0.799	38.22	-0.002	-0.762	75.99	-0.002	-0.702	74.12
25	0.005	0.789	32.17	0.005	0.798	28.96	-0.003	-0.737	74.95	-0.003	-0.716	77.51
26	0.007	0.801	45.84	0.003	0.788	49.09	-0.002	-0.728	74.73	-0.003	-0.658	76.02
27	0.005	0.811	43.53	0.005	0.830	37.86	-0.002	-0.728	74.92	-0.003	-0.667	75.52

SeCoS Corporation

Resistance to Solder Heat Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 245℃ ± 5℃, 5Sec

Test Date: 2020.05.28

Test Standard : JESD22 STANDARD Method-B106

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
28	0.003	0.816	31.59	0.007	0.782	42.79	-0.002	-0.692	76.53	-0.001	-0.697	74.81
29	0.000	0.788	50.31	0.006	0.795	51.62	-0.001	-0.715	75.99	-0.002	-0.747	76.63
30	0.004	0.790	41.35	0.001	0.780	31.85	-0.001	-0.678	75.07	-0.001	-0.727	78.72
31	0.004	0.823	49.89	0.003	0.785	29.17	-0.002	-0.727	77.65	-0.001	-0.685	78.67
32	0.002	0.786	28.70	0.005	0.805	42.50	-0.001	-0.761	75.17	-0.001	-0.714	74.32
33	0.006	0.805	40.35	0.006	0.791	50.07	-0.001	-0.675	76.98	-0.000	-0.687	74.57
34	0.006	0.784	33.94	0.001	0.829	29.67	-0.002	-0.750	77.20	-0.001	-0.731	77.57
35	0.000	0.792	33.44	0.005	0.793	30.78	-0.001	-0.691	75.12	-0.001	-0.687	76.30
36	0.006	0.795	29.77	0.003	0.787	46.45	-0.000	-0.702	74.73	-0.001	-0.674	76.05
37	0.000	0.820	48.67	0.006	0.826	40.60	-0.002	-0.754	76.26	-0.002	-0.761	78.15
38	0.006	0.803	50.41	0.003	0.829	36.07	-0.002	-0.688	74.92	-0.002	-0.716	75.36
39	0.007	0.795	34.19	0.006	0.811	42.22	-0.002	-0.717	75.48	-0.001	-0.664	74.08
40	0.004	0.786	34.55	0.002	0.809	50.48	-0.000	-0.704	78.29	-0.001	-0.666	77.32
41	0.006	0.810	51.63	0.001	0.820	30.68	-0.002	-0.706	74.46	-0.001	-0.744	77.84
42	0.002	0.792	48.50	0.004	0.793	32.47	-0.002	-0.729	74.39	-0.003	-0.658	74.18
43	0.003	0.789	43.52	0.005	0.810	41.06	-0.000	-0.704	74.91	-0.001	-0.740	76.98
44	0.005	0.814	31.21	0.006	0.825	37.68	-0.001	-0.697	75.18	-0.003	-0.697	75.87
45	0.001	0.787	51.63	0.002	0.804	51.90	-0.001	-0.742	78.41	-0.002	-0.722	77.53
46	0.007	0.791	45.17	0.003	0.781	36.19	-0.000	-0.686	78.69	-0.002	-0.761	77.57
47	0.004	0.813	50.86	0.005	0.811	48.08	-0.002	-0.704	76.29	-0.001	-0.690	75.01
48	0.003	0.813	29.55	0.003	0.801	43.34	-0.001	-0.708	78.09	-0.001	-0.672	77.31
49	0.001	0.831	49.41	0.005	0.781	48.26	-0.001	-0.735	78.05	-0.002	-0.683	75.24
50	0.004	0.825	40.15	0.003	0.813	37.88	-0.002	-0.661	77.86	-0.001	-0.724	77.59
51	0.001	0.818	38.50	0.002	0.797	50.77	-0.002	-0.681	76.85	-0.001	-0.684	74.40
52	0.006	0.796	29.80	0.001	0.800	30.79	-0.002	-0.712	77.39	-0.002	-0.665	77.27
53	0.002	0.787	40.77	0.004	0.819	39.48	-0.002	-0.670	78.50	-0.002	-0.735	77.09
54	0.002	0.779	37.28	0.004	0.828	37.59	-0.002	-0.717	75.24	-0.003	-0.684	74.59

SeCoS Corporation

Resistance to Solder Heat Test Data

Report No : T200529-T3585S

Part No : SST3585S-C

Test Equipment: JUNO Test System DTS-1000

Test Condition : N-Channel (I_{DSS}<1μA@V_{DS}=20V; $V_{GS(th)}$<1.2V@I_D=250μA;
$R_{DS(ON)}$<75mΩ@V_{GS}=4.5V, I_D=3.5A)
P-Channel (I_{DSS} < -1μA@V_{DS}=-20V; $V_{GS(th)}$ < -1.2V@I_D=-250μA;
$R_{DS(ON)}$ < 160mΩ@V_{GS}=-4.5V, I_D=-2.5A)

Test Condition: 245℃ ± 5℃, 5Sec

Test Date: 2020.05.28

Test Standard : JESD22 STANDARD Method-B106

Operator: Leo Hsia

Test Result: PASS

No	N-Channel						P-Channel					
	Before			After			Before			After		
	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)	I_{DSS} (μA)	$V_{GS(th)}$ (V)	$R_{DS(ON)}$ (mΩ)
55	0.007	0.830	41.65	0.005	0.788	32.19	-0.000	-0.697	74.49	-0.001	-0.734	74.91
56	0.004	0.792	49.16	0.001	0.782	49.13	-0.003	-0.659	73.71	-0.002	-0.677	73.84
57	0.002	0.816	40.19	0.002	0.790	37.58	-0.001	-0.759	77.24	-0.002	-0.683	76.01
58	0.005	0.824	47.65	0.002	0.826	31.82	-0.002	-0.729	75.36	-0.001	-0.689	77.31
59	0.007	0.825	39.12	0.002	0.802	31.96	-0.003	-0.663	77.35	-0.002	-0.658	74.19
60	0.005	0.811	33.84	0.007	0.785	34.35	-0.003	-0.715	77.09	-0.000	-0.664	78.13
61	0.003	0.805	44.71	0.003	0.820	45.19	-0.003	-0.700	75.51	-0.001	-0.712	76.93
62	0.006	0.830	40.16	0.003	0.780	34.60	-0.001	-0.737	77.36	-0.001	-0.740	76.84
63	0.001	0.798	42.40	0.001	0.802	36.97	-0.002	-0.742	75.96	-0.003	-0.732	78.10
64	0.001	0.821	45.45	0.001	0.820	28.56	-0.001	-0.658	73.81	-0.002	-0.686	77.00
65	0.005	0.828	43.91	0.002	0.821	31.63	-0.000	-0.711	74.36	-0.001	-0.728	77.99
66	0.002	0.792	44.57	0.000	0.803	40.29	-0.000	-0.748	74.78	-0.001	-0.729	74.55
67	0.006	0.824	42.17	0.004	0.822	40.18	-0.001	-0.760	74.46	-0.003	-0.709	75.27
68	0.001	0.802	32.50	0.004	0.802	38.99	-0.002	-0.751	74.82	-0.001	-0.687	75.72
69	0.001	0.790	49.77	0.000	0.810	38.70	-0.003	-0.701	75.08	-0.001	-0.752	75.38
70	0.003	0.813	29.96	0.002	0.782	38.61	-0.001	-0.757	75.20	-0.001	-0.751	76.32
71	0.001	0.809	49.14	0.001	0.798	43.70	-0.002	-0.660	75.37	-0.000	-0.748	75.10
72	0.000	0.797	29.72	0.003	0.808	39.84	-0.001	-0.753	77.55	-0.000	-0.680	74.43
73	0.003	0.817	44.27	0.001	0.827	37.96	-0.001	-0.715	78.45	-0.001	-0.731	77.69
74	0.003	0.829	48.14	0.004	0.796	48.99	-0.002	-0.697	74.17	-0.001	-0.665	77.44
75	0.007	0.787	29.65	0.003	0.807	35.17	-0.002	-0.728	73.76	-0.002	-0.700	78.12
76	0.001	0.794	31.99	0.002	0.830	38.59	-0.002	-0.674	73.56	-0.002	-0.737	74.04
77	0.000	0.819	28.83	0.003	0.785	36.68	-0.003	-0.671	76.51	-0.001	-0.663	74.83

Made By: King Huang

Approval: Peter Yang